Wafer Analysis Report
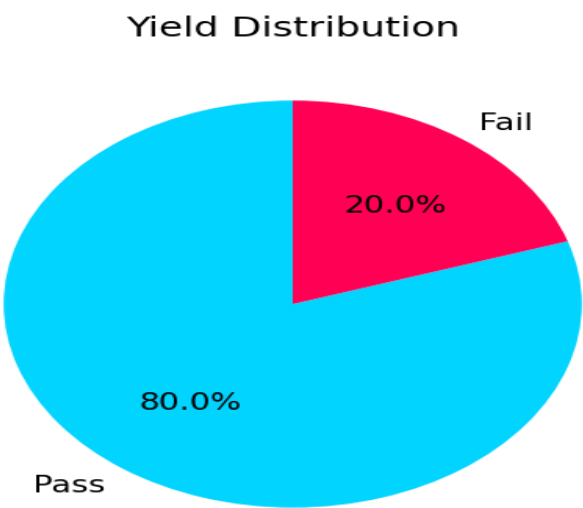
Generated: 2025-12-21 18:48:09
Total Wafers: 10
Defective Wafers: 2
Yield Rate: 80.00%

Lot-Level Summary

Yield Distribution

Defect Pattern Distribution

Pattern	Count	Percentage
Scratch	1	10.0%
Donut	1	10.0%

Individual Wafer Analysis

Wafer ID	W1
File Name	wafer1.npy
Verdict	PASS
Confidence	98.5%
Severity	None

Wafer ID	W2
File Name	wafer2.npy
Verdict	FAIL
Confidence	99.1%
Severity	High